April 2000

# QFET™

## **FQP22P10**

#### 100V P-Channel MOSFET

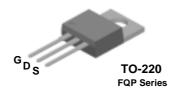
#### **General Description**

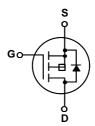
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

#### **Features**

- -22A, -100V,  $R_{DS(on)} = 0.125\Omega$  @ $V_{GS} = -10$  V
- Low gate charge (typical 40 nC)
- Low Crss (typical 160 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating





### Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQP22P10	Units
V <sub>DSS</sub>	Drain-Source Voltage		-100	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	C)	-22	А
	- Continuous (T <sub>C</sub> = 100°C)		-15.6	А
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-88	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	710	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-22	А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	12.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-6.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		125	W
	- Derate above 25°C		0.83	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.2	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-100			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$ , Referenced to 25°C		-0.1		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -100 V, V <sub>GS</sub> = 0 V			-1	μΑ
		V <sub>DS</sub> = -80 V, T <sub>C</sub> = 125°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
On Cha	aracteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -11 A		0.096	0.125	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -40 V, I <sub>D</sub> = -11 A (Note 4)		13.5		S
C <sub>oss</sub> C <sub>rss</sub>	Output Capacitance  Reverse Transfer Capacitance	f = 1.0 MHz		460 160	600 200	pF pF
Coss	<u>'</u>	f = 1.0 MHz				-
0 1/ 1			·			
	ing Characteristics	1			1	
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -50 \text{ V}, I_{D} = -22 \text{ A},$		17	45	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		170	350	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	(Note 4, 5		60	130	ns
t <sub>f</sub>	Turn-Off Fall Time	,	′	110	230	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = -80 \text{ V}, I_{D} = -22 \text{ A},$		40	50	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -10 V		7.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5	)	21		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
	Maximum Continuous Drain-Source Diode Forward Current				-22	Α
I <sub>S</sub>					-88	Α
I <sub>S</sub> I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	Forward Current			00	<i>,</i> ,
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F Drain-Source Diode Forward Voltage	Forward Current $V_{GS} = 0 \text{ V, I}_{S} = -22 \text{ A}$			-4.0	V
I <sub>S</sub> I <sub>SM</sub> V <sub>SD</sub> t <sub>rr</sub>						

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.2mH, I<sub>AS</sub> = -22A, V<sub>DD</sub> = -25V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub> ≤ -22A, di/dt ≤ 300A/μs, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width ≤ 300 $\mu$ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

## **Typical Characteristics**

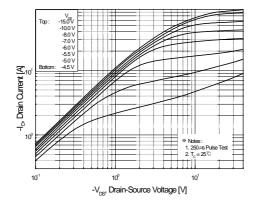


Figure 1. On-Region Characteristics

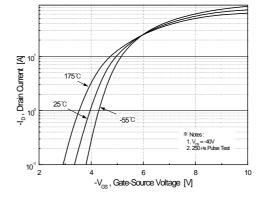


Figure 2. Transfer Characteristics

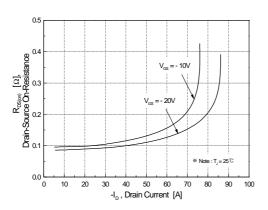


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

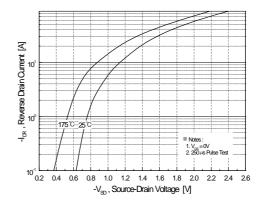


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

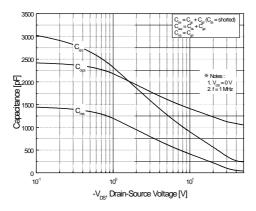


Figure 5. Capacitance Characteristics

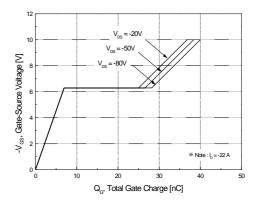
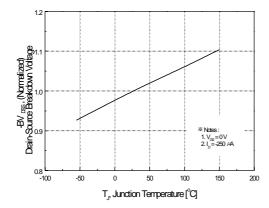


Figure 6. Gate Charge Characteristics

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## Typical Characteristics (Continued)



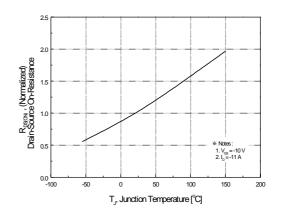
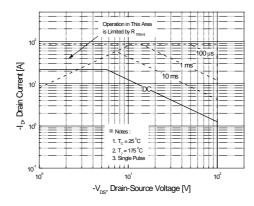


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



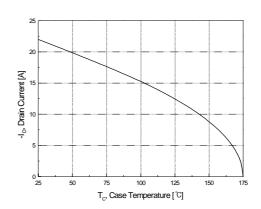


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

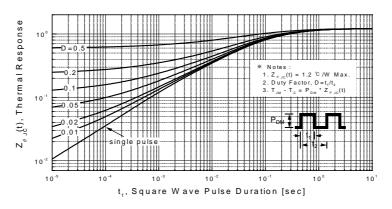
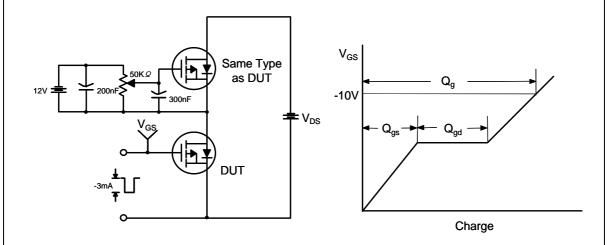


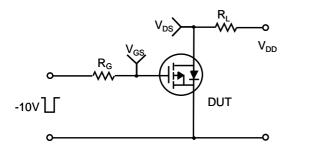
Figure 11. Transient Thermal Response Curve

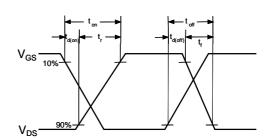
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#### **Gate Charge Test Circuit & Waveform**

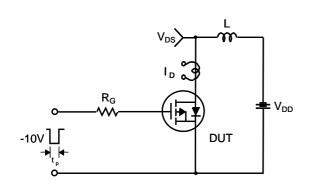


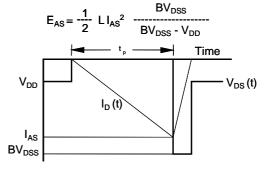
#### **Resistive Switching Test Circuit & Waveforms**



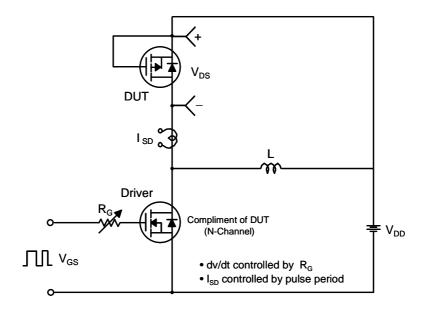


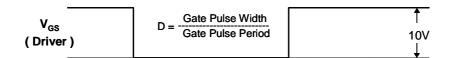
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

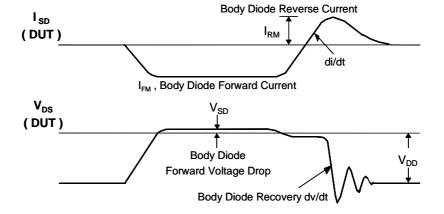


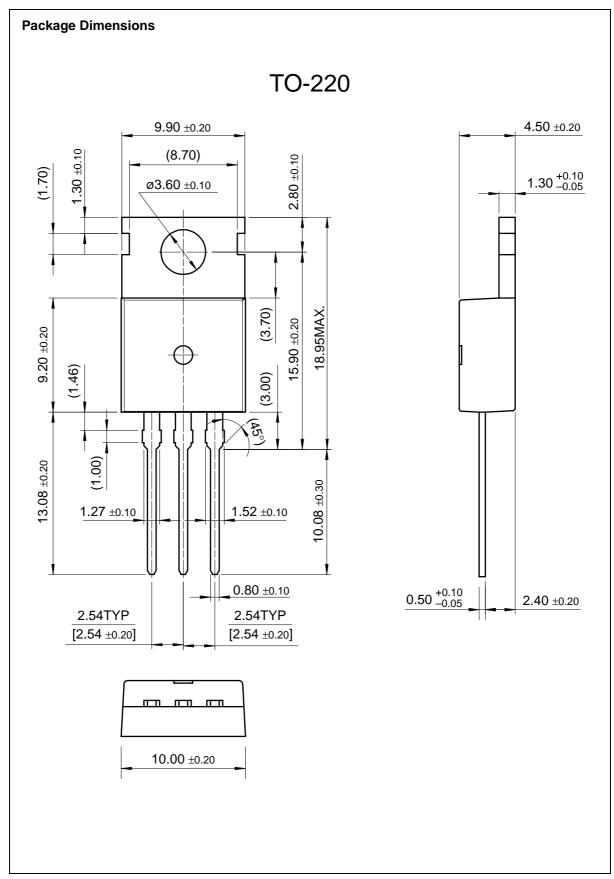


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms









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